

GB-RADNEXT Workshop 2024

Thursday, 13 June 2024

Session 4: Alternative Probes for SEE Testing (09:10 - 10:50)

time	[id] title	presenter
09:10	[56] Session introduction	BÉLANGER-CHAMPAGNE (TRIUMF), Chair: Camille
09:15	[23] Talk 1: Laser-driven beams for radiation-to-electronics study	VERSACI (ELI ERIC), Roberto
09:35	[24] Talk 2: How synchrotron light sources can help overcome the major limitations related to Heavy Ions Single Event Effects testing in electronic circuits	CAPRIA (ESRF), Ennio
09:55	[26] Talk 3: How pulsed laser SEE testing aids the space qualification of EEE components	SHARP (RADTEST), Richard
10:15	[25] Talk 4: Muon-induced Soft Errors in FinFET and Planar SRAMs	HASHIMOTO (KYOTO UNIVERSITY), Masanori
10:35	[44] Discussion with the audience	